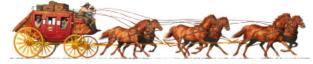


The Value of Durable Materials in Maximizing Your Investment in Solar Energy

Jon Previtali, Director of Technology & Technical Services PV Magazine Webinar, November 2017

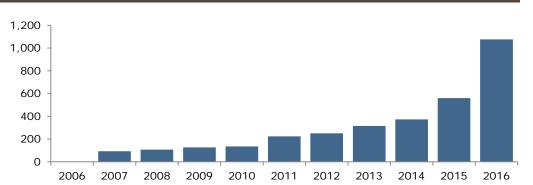
Together we'll go far



Wells Fargo Renewable Energy & Environmental Finance (REEF)

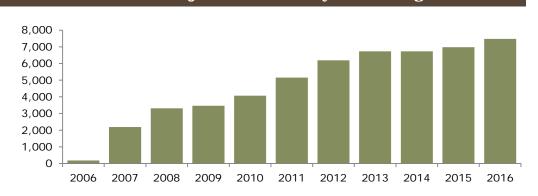
- Established in 2006 to provide tax equity capital for the renewable energy industry.
- Today, the group has **28 professionals with decades of combined experience in renewable energy.**
- Collaboration with Wells Fargo CleanTech Banking which offers traditional banking services & relationship management.

Cumulative Solar Projects Financed by Wells Fargo (MWDC)





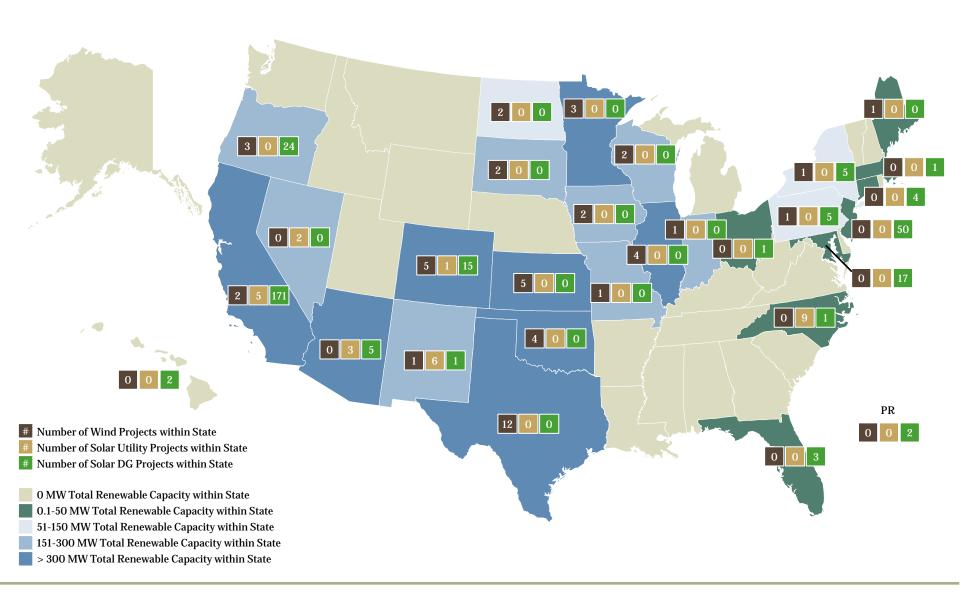
Cumulative Wind Projects Financed by Wells Fargo (MWAC)

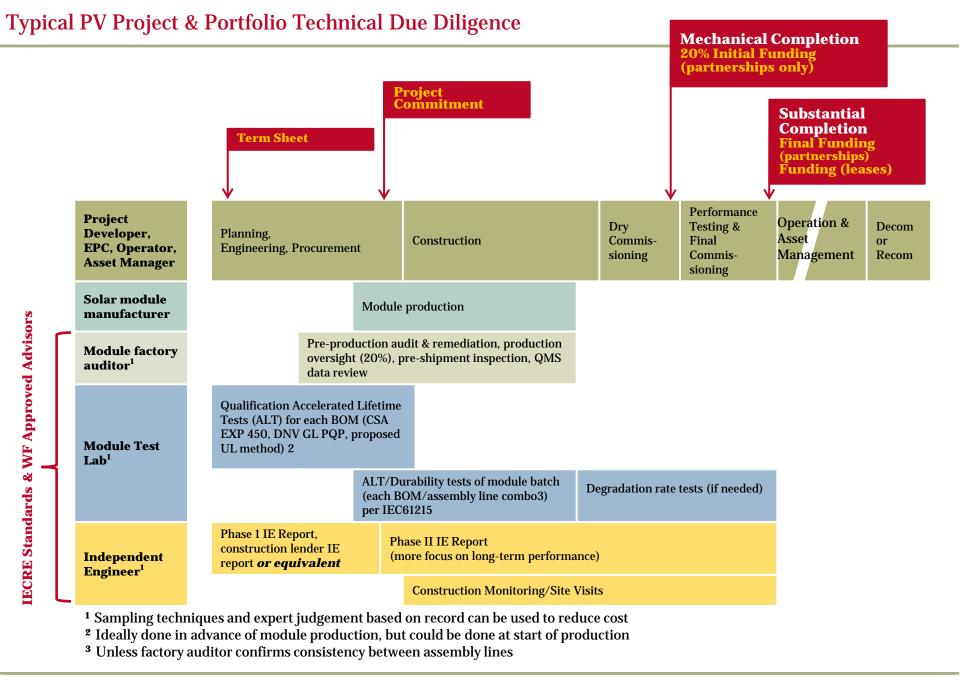




Wells Fargo Renewable Energy & Environmental Finance (REEF)

8+GW portfolio comprised of 50+ Wind projects and 300+ Solar projects



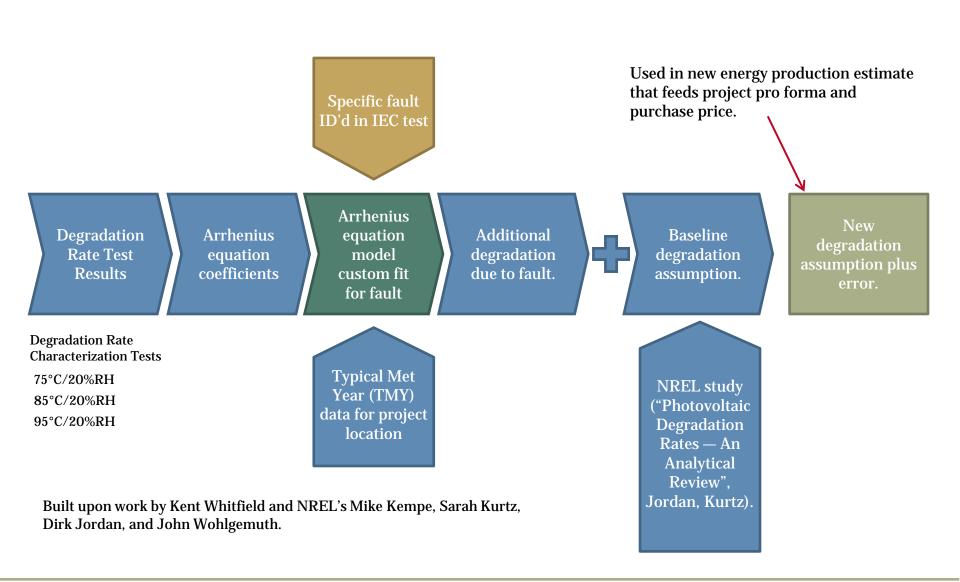


Example of PV Module Accelerated Lifetime Testing (ALT) Scope of Work

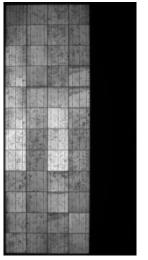
	Characteristics Communication	Test Module Count or Component Sample															
Weeks:	Standard or Source	Count	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
Days at Lab:				7	14	21	28	35	42	49	56	63	70	77	84	91	98
Air Shipment			×		14	21	20	33	42	45	30	03	70	- //	04	91	36
Sample prep, outdoor preconditioning (Clause 5 61215)				x													+
Visual, EL, IV, Flash Test, Wet Leakage (when required)				X	x	x		×	x	x	x			x			x
Module Qualification Tests (IEC and Extended Testing)				^					_ ^		^			^			
TC (Thermal Cycling)	NREL Qualification Plus					200		500		800							+
DH (Damp Heat)	NREL Qualification Plus					200		500		800	1000			1500			2000
DML/TC50/HF30	NREL Qualification Plus	varies				x		300			1000			1300			2000
PID (Potential Induced Degradation)	NREL Qualification Plus					192											+
Statistical Module Batch Tests (each BOM/factory combo						152											-
·	IEC 61215					200											
TC (Thermal Cycling) DH (Damp Heat)	IEC 61215	30 (6 per test) for 95%				200		500			1000						2000
TC50/HF10 (Thermal Cycling/Humidity Freeze)	IEC 61215	confidence level that			x			500			1000						2000
	IEC 61215	90% of modules will be			96												
PID (Potential Induced Degradation) DML (Dynamic Mechanical Load)	IEC 61215	defect free			96				X								
	IEC 61215	20 of existing sample set							X								
LID (Light Induced Degradation) PAN file validation/creation (for PVSyst)	IEC 61215	20 or existing sample set						X									
	IEC 61853-1	3 of existing sample set						X									+
IAM (Incident Angle Modifier) loss validation	IEC 61215	All -6		X													-
Bypass Diode Test	IEC 61215	All of sample set		X													
Degradation Rate Characterization Tests*	NREL special for Wells Fargo							500			1000			1500			2000
75°C/20%RH	-	6 (1 with defect + 1															
85°C/20%RH	NREL special for Wells Fargo	control with no defect						500			1000			1500			2000
95°C/20%RH	NREL special for Wells Fargo	per test)						500			1000			1500			2000
Other tests**																	
Modules:		_															
Hot Spot Test	NREL Qualification Plus/ASTM E2481-06	5			х												
Components:		_															
UV Exposure of Junction Box	NREL Qualification Plus	5						500									
Bypass Diode and Junction Box Thermal Test	NREL Qualification Plus	5			96												
UV Exposure for Encapsulants	NREL Qualification Plus	5															00 hours>>
UV Exposure for Backsheets	NREL Qualification Plus	12															00 hours>>
UV Exposure for Cables and Connectors	NREL Qualification Plus	3														~40	00 hours>>
Result checks/Reports				Initial	Check 1	Check 2		Check 3	Check 4	Check 5	IEC 61215						Extended
				Check							Report,						Test
											Stop deg						Report,
											rate char tests if no						Degradati on Rate
											fault						On Rate Character
											found						ization (if
											Iounu						needed)

^{*}Initiated for each BOM/factory combo, but stopped if no fault found in IEC baseline

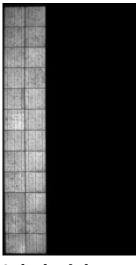
^{**}Performed if there is a reason for concern, e.g. historical defect, known issue, significantly new component, material or design, etc.



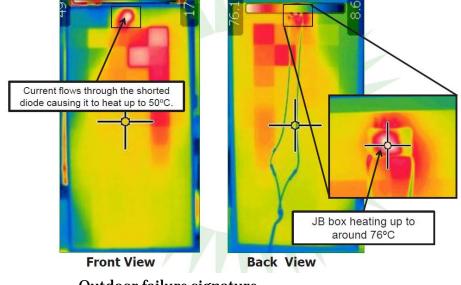
Bypass diode failures



Diode failure at TC400

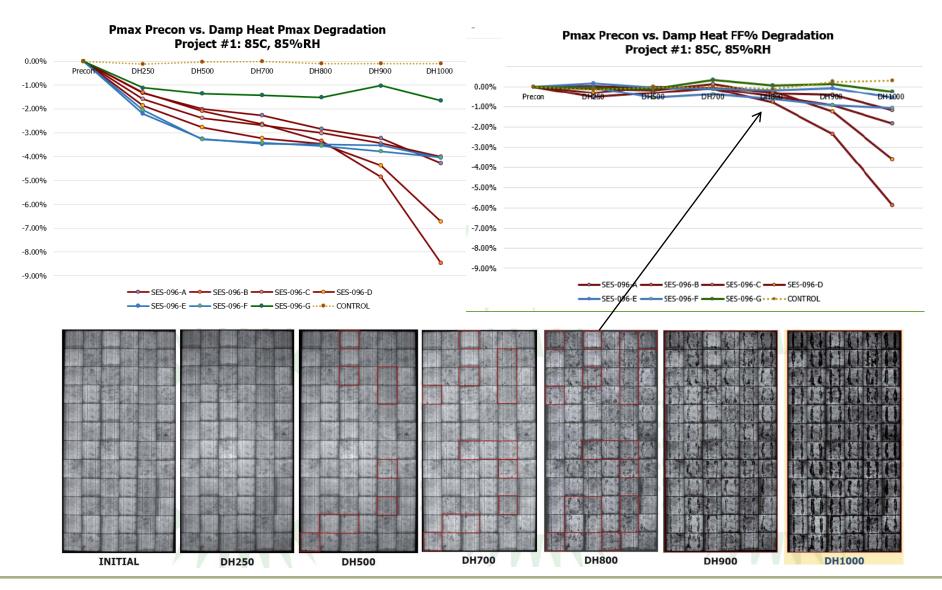


2-diodes fail at TC600



Outdoor failure signature

Accelerated cell corrosion



Junction box lid failures



Lifted lid at one corner. The lid still tightly held flat at the other 3-corner pins.



Resulting corrosion after 3 years near coast

Lid Type	Stress	Amount	N	Failure Rate	
1	DH	1000	23	52%	2014 testing
2	DH	1000	145	2%	2014 testing
2	DH	2000	23	4%	2014 testing
2	HF	20/40	12	0%	RETC
2	HF	60	12	8%	RETC
2	HF	80	12	17%	RETC
2	HF	100	12	25%	RETC
2	TC / HF	50 / 20	20	10%	2014 + RETC
2	TC/HF	100 / 40	10	0%	RETC
4	DH	1000	24	0%	
4	DH	2000	22	0%	
4	HF	20/40/60/80	36	0%	DETC
4	HF	100	10	0%	RETC
4	TC/HF	50 / 20	34	0%	
4	TC/HF	100 / 40	30	0%	

Thank you!

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